

# Supplementary Materials for “Mechanical Property Measurements Enabled by Short Term Fourier Transform of Atomic Force Microscopy Thermal Deflection Analysis”

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## 1. Equations of Dispersion Relations for Three Cantilever Models

### 1.1. Solution to Model 1 Dispersion

$$\sinh(k_n L) \cos(k_n L) - \sin(k_n L) \cosh(k_n L) = \frac{(k_n L)^3 k_c}{3k^*} (1 + \cos(k_n L) \cosh(k_n L)) \quad (1)$$

### 1.2. Solution to Model 2 Dispersion

$$\begin{aligned} & -(\cosh(k_n L_1) \sin(k_n L_1) - \sinh(k_n L_1) \cos(k_n L_1))(1 + \cos(k_n L') \cosh(k_n L')) \\ & -(\cosh(k_n L') \sin(k_n L') - \sinh(k_n L') \cos(k_n L'))(1 - \cos(k_n L_1) \cosh(k_n L_1)) \\ & = 2k_n^3 \frac{EI}{k^*} [1 + \cos(k_n (L_1 + L')) \cosh(k_n (L_1 + L'))] \end{aligned} \quad (2)$$

### 1.3. Solution to Model 3 Dispersion

$$\frac{k^*}{k_c} = \frac{-B \pm \sqrt{B^2 - 4AC}}{6A} \quad (3)$$

$$A = \left(\frac{\kappa}{k^*}\right) \left(\frac{h}{L_1}\right)^2 (1 - \cos(x) \cosh(xL_1))(1 + \cos(xL') \cosh(xL')) \quad (4)$$

$$B = B_1 + B_2 + B_3 \quad (5)$$

$$C = 2(xL_1)^4 (1 + \cos(xL_1) \cosh(xL_1)) \quad (6)$$

$$\begin{aligned} B_1 = \left(\frac{h}{L_1}\right)^2 (xL_1)^3 & \left( \sin^2(\alpha) + \frac{\kappa}{k_c} \cos^2(\alpha) \right) \\ & [(1 + \cos(xL') \cosh(xL')) (\sin(xL_1) \cosh(nL_1) + \cos(xL_1) \sinh(xL_1)) \\ & - (1 - \cos(nL_1) \cosh(nL_1)) (\sin(xL') \cosh(xL') + \cos(xL') \sinh(xL'))] \end{aligned} \quad (7)$$

$$B_2 = 2 \left( \frac{h}{L_1} \right) (xL_1)^2 \left( \frac{\kappa}{k_c} \cos(\alpha) \sin(\alpha) \right) \\ [(1 + \cos(xL') \cosh(xL')) (\sin(xL_1) \sinh(nL_1)) \\ + (1 - \cos(nL_1) \cosh(nL_1)) (\sin(xL') \sinh(xL'))] \quad (8)$$

$$B_3 = (xL_1) (\cos^2(\alpha) + \frac{\kappa}{k_c} \sin^2(\alpha)) \\ [(1 + \cos(xL') \cosh(xL')) (\sin(xL_1) \cosh(nL_1) - \cos(xL_1) \sinh(xL_1)) \\ - (1 - \cos(nL_1) \cosh(nL_1)) (\sin(xL') \cosh(xL') - \cos(xL') \sinh(xL'))] \quad (9)$$

$$G^* = \left( \frac{2 - \nu_1}{G_1} + \frac{2 - \nu_2}{G_2} \right)^{-1} \quad (10)$$

$$G = \frac{1}{2} \left( \frac{E}{1 + \nu} \right) \quad (11)$$

$$\kappa = 8G^* a = \frac{8G^* k^*}{2E^*} = \frac{4k^* \left( \frac{2 - \nu_1}{\frac{1}{2} \frac{E_1}{1 + \nu_1}} \right) + \left( \frac{2 - \nu_1}{\frac{1}{2} \frac{E_1}{1 + \nu_1}} \right)}{E^*} \quad (12)$$

## 2. Cantilever Frequency Power Spectrum

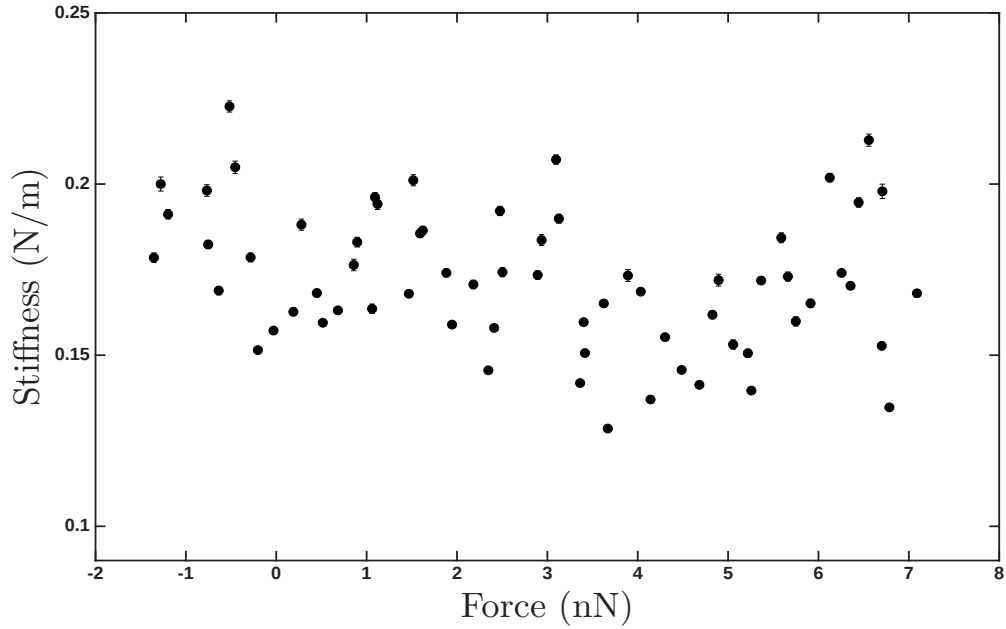


Fig. S1. *tiffness<sub>p</sub> plot Stiffness versus normal force determined from fit of the first normal resonant mode peak in the power spectra of the contact port*

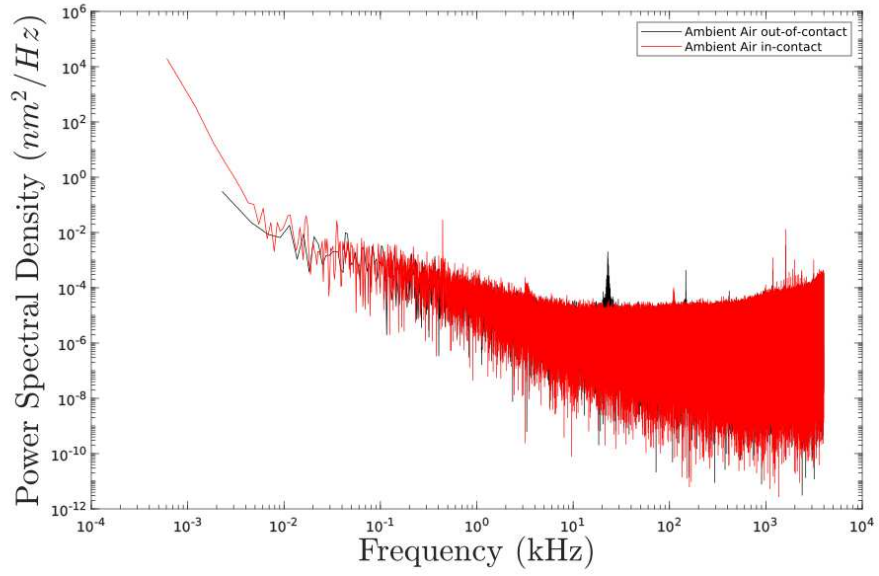


Fig. S2. Power Spectral Density (nm<sup>2</sup>/Hz) versus Frequency (kHz) for the out-of-contact portion of a diamond-coated probe on a silicon substrate. The out-of-contact portion is in red, highlighting the change in the resonant peak locations and shapes between the two stages of the measurement.

### 3. Elastic Modulus Determination of PEO

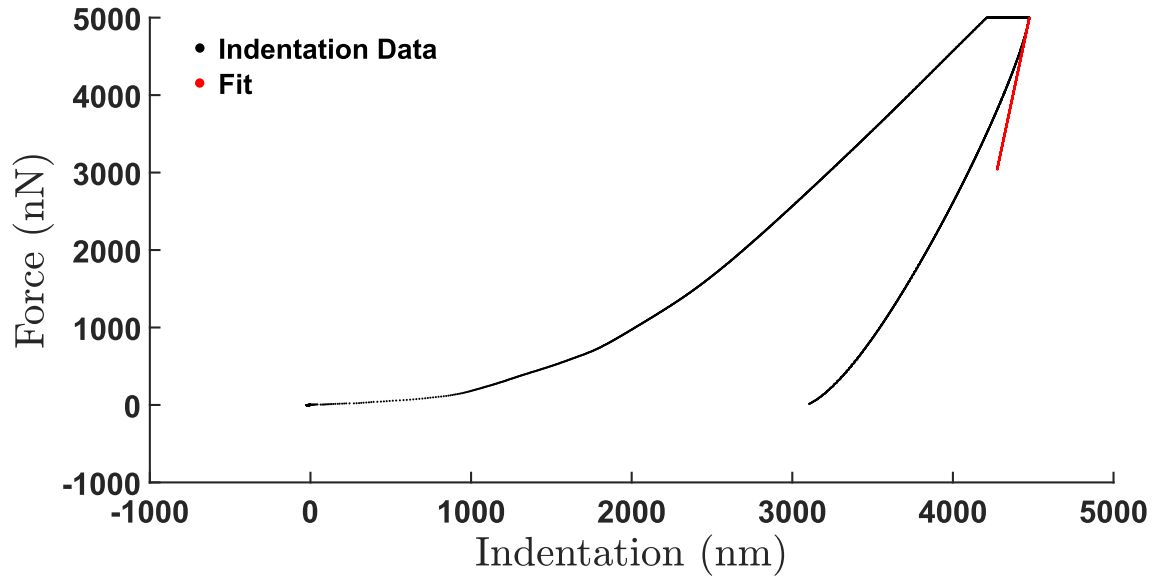


Fig. S3. Example Elastic unloading curves for the PEO sample obtained from nanoindentation experiments with a Berkovich indenter. Slope of curve in red is the linear fit used to determine the Young's modulus of the sample.